

# HQ:CSC37/tipless/No Al

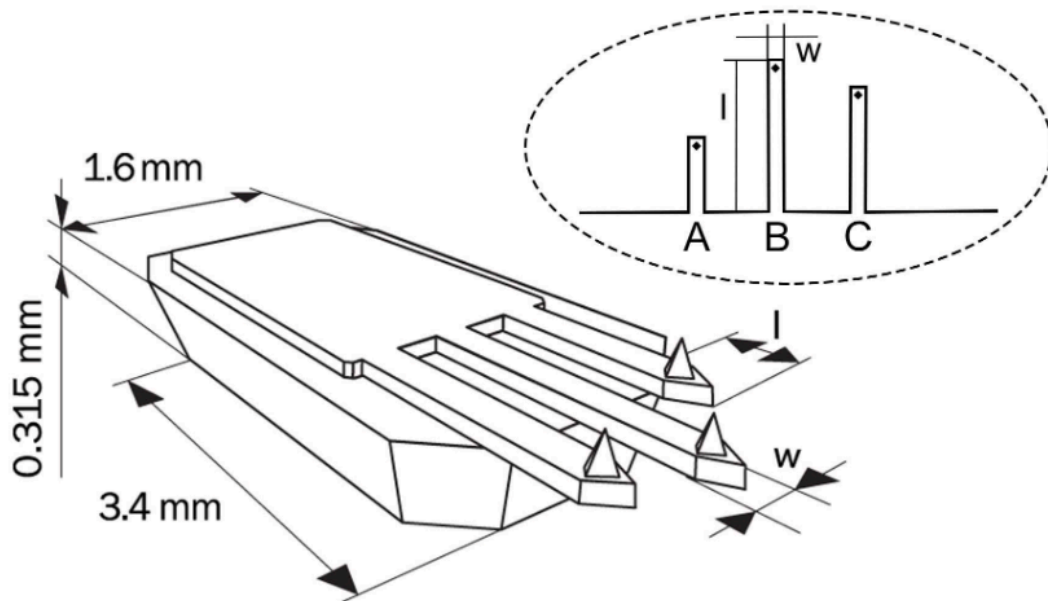
## Tipless AFM Probe with 3 Different Contact Mode AFM Cantilevers

AFM probes of the HQ:CSC37 series have three different tipless contact mode AFM cantilevers on one side of the holder chip. They can be used in various applications.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

### Coating

none



## AFM Probe Specifications

### AFM Tip

SHAPE
Tipless

### AFM Cantilever

CANTILEVER	SHAPE	FORCE CONST.	RES. FREQ.	LENGTH	WIDTH	THICKNESS
Cantilever A	Beam	0.8 N/m (0.3 – 2 N/m)*	40 kHz (30 – 55 kHz)*	250 $\mu\text{m}$ (1 – 255 $\mu\text{m}$ )*	35 $\mu\text{m}$ (32 – 38 $\mu\text{m}$ )*	2 $\mu\text{m}$ (1.5 – 2.5 $\mu\text{m}$ )*
Cantilever B	Beam	0.3 N/m (0.1 – 0.6 N/m)*	20 kHz (15 – 30 kHz)*	350 $\mu\text{m}$ (1 – 355 $\mu\text{m}$ )*	35 $\mu\text{m}$ (32 – 38 $\mu\text{m}$ )*	2 $\mu\text{m}$ (1.5 – 2.5 $\mu\text{m}$ )*
Cantilever C	Beam	0.4 N/m (0.1 – 1 N/m)*	30 kHz (20 – 40 kHz)*	300 $\mu\text{m}$ (1 – 305 $\mu\text{m}$ )*	35 $\mu\text{m}$ (32 – 38 $\mu\text{m}$ )*	2 $\mu\text{m}$ (1.5 – 2.5 $\mu\text{m}$ )*

\* typical values